

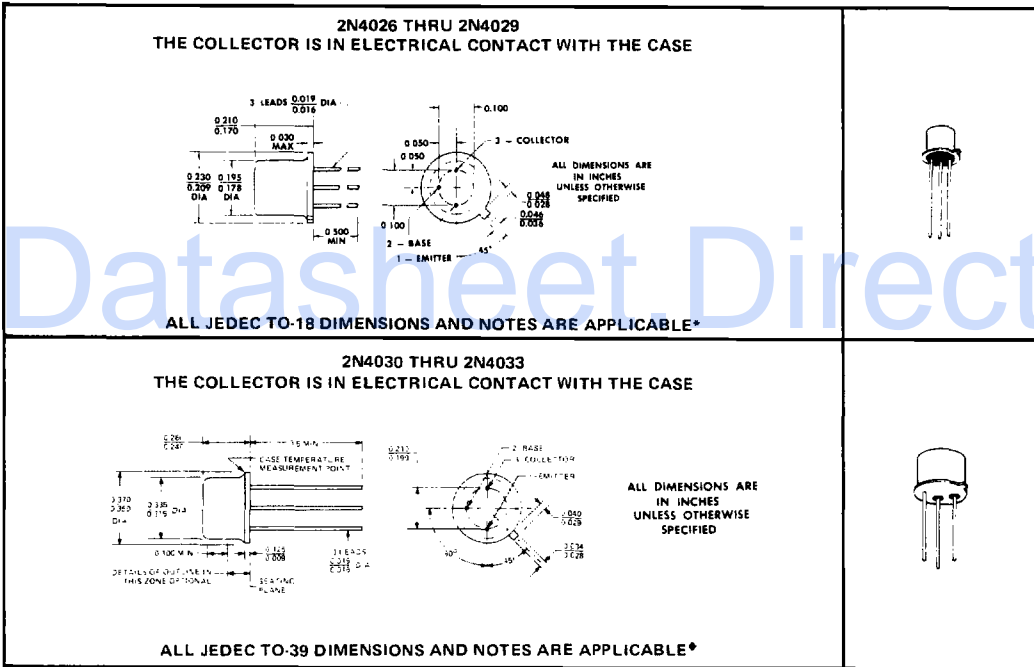
# TYPES 2N4026 THRU 2N4033 P-N-P SILICON TRANSISTORS

BULLETIN NO. DLS 7311982, MARCH 1973

## MEDIUM POWER P-N-P TRANSISTORS FOR COMPUTER MEMORY APPLICATIONS

- Increased Dissipation at 25°C Case Temperature . . . 10 W Max (2N4030 thru 2N4033)
- High  $V_{(BR)CEO}$  . . . 80 V Min (2N4027, 2N4029, 2N4031, 2N4033)

mechanical data



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absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

	2N4026	2N4027	2N4030	2N4031	UNIT
	2N4028	2N4029	2N4032	2N4033	
Collector-Base Voltage	-60*	-80*	-60*	-80*	V
Collector-Emitter Voltage (See Note 1)	-60*	-80*	-60*	-80*	V
Emitter-Base Voltage		-5*		-5*	V
Continuous Collector Current		-1*		-1*	A
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 2)		0.5*		0.8*	W
Continuous Device Dissipation at (or below) 25°C Case Temperature (See Note 3)		2*		10† 4*	W
Storage Temperature Range		-65 to 200*		-65 to 200*	°C
Lead Temperature 1/16 Inch from Case for 60 Seconds		300*		300*	°C

- NOTES: 1. These values apply between 0 and 10 mA collector current when the base-emitter diode is open-circuited.  
 2. Derate linearly to 200°C free-air temperature at the rates of 2.86 mW/°C for 2N4026 through 2N4029 and 4.56 mW/°C for 2N4030 through 2N4033  
 3. Derate linearly to 200°C case temperature at the following rates: 11.4 mW/°C for the 2-watt rating, 57.1 mW/°C for the 10-watt rating, and 22.8 mW/°C for the 4-watt rating.

\*The JEDEC registered outline for these devices is TO-5. TO-39 falls within TO-5 with the exception of lead length.  
 †JEDEC registered data. This data sheet contains all applicable registered data in effect at the time of publication.  
 ‡ This value is guaranteed by Texas Instruments in addition to the JEDEC registered value which is also shown.

USES CHIP P16

# TYPES 2N4026 THRU 2N4033

## P-N-P SILICON TRANSISTORS

\*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	2N4026 2N4030		2N4027 2N4031		2N4028 2N4032		2N4029 2N4033		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
$V_{(BR)CBO}$	Collector-Base Breakdown Voltage $I_C = -10 \mu A, I_E = 0$	-60		-80		-60		-80		V	
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage See Note 4 $I_C = -10 mA, I_B = 0$	-60		-80		-60		-80		V	
$V_{(BR)EBO}$	Emitter-Base Breakdown Voltage $I_E = -10 \mu A, I_C = 0$	-5		-5		-5		-5		V	
$I_{CBO}$	Collector Cutoff Current $V_{CB} = -50 V, I_E = 0$ $V_{CB} = -60 V, I_E = 0$ $V_{CB} = -50 V, I_E = 0, T_A = 150^\circ C$ $V_{CB} = -60 V, I_E = 0, T_A = 150^\circ C$		-50				-50			nA	
					-50				-50	nA	
			-50				-50				$\mu A$
					-50				-50		$\mu A$
$I_{EBO}$	Emitter Cutoff Current $V_{EB} = -5 V, I_C = 0$ $V_{CE} = -5 V, I_C = -100 \mu A$		-10		-10		-10		-10	$\mu A$	
$h_{FE}$	Static Forward Current Transfer Ratio $V_{CE} = -5 V, I_C = -100 mA$ $V_{CE} = -5 V, I_C = -100 mA, T_A = -55^\circ C$ $V_{CE} = -5 V, I_C = -500 mA$ $V_{CE} = -5 V, I_C = -1 A$	See Note 4	30	120	30	120	75	300	75	300	
			15		15		40		40		
			25		25		70		70		
			15		10		40		25		
$V_{BE}$	Base-Emitter Voltage $I_B = -15 mA, I_C = -150 mA$ $V_{CE} = -0.5 V, I_C = -500 mA$ $V_{CE} = -1 V, I_C = -1 A$	See Note 4	-0.9		-0.9		-0.9		-0.9		V
			-1.1		-1.1		-1.1		-1.1		
			-1.2				-1.2				
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage $I_B = -15 mA, I_C = -150 mA$ $I_B = -50 mA, I_C = -500 mA$ $I_B = -100 mA, I_C = -1 A$	See Note 4	-0.15		-0.15		-0.15		-0.15		V
			-0.5		-0.5		-0.5		-0.5		
			-1				-1				
$ h_{fe} $	Small-Signal Common-Emitter Forward Current Transfer Ratio $V_{CE} = -10 V, I_C = -50 mA, f = 100 MHz$	1	4	1	4	1.5	5	1.5	5		
$C_{cb}$	Collector-Base Capacitance $V_{CB} = -10 V, I_E = 0, f = 1 MHz$ See Note 5		20		20		20		20	pF	
$C_{ibo}$	Common-Base Open-Circuit Input Capacitance $V_{EB} = -0.5 V, I_C = 0, f = 1 MHz$		110		110		110		110	pF	

NOTES: 4. These parameters must be measured using pulse techniques.  $t_w = 300 \mu s$ , duty cycle  $\leq 1\%$ .

5.  $C_{cb}$  measurement employs a three-terminal capacitance bridge incorporating a guard circuit. The emitter is connected to the guard terminal of the bridge.

\*JEDEC registered data

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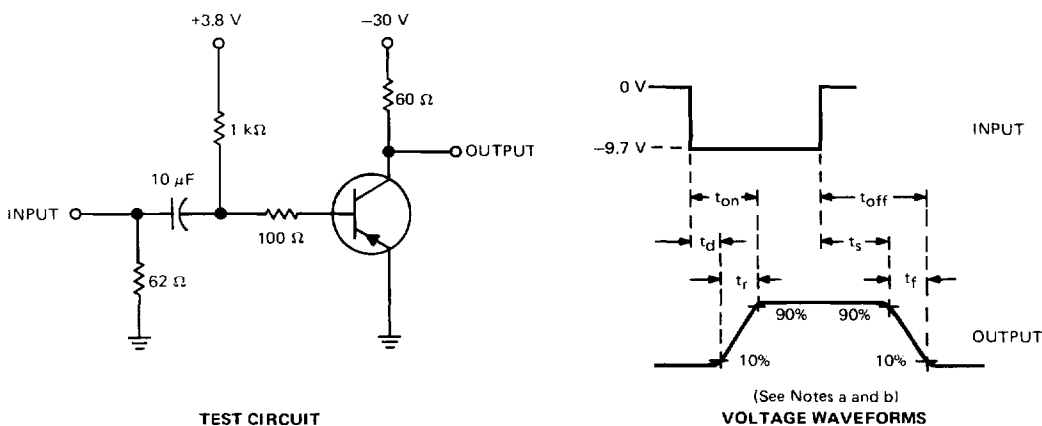
switching characteristics at 25°C free-air temperature

PARAMETER		TEST CONDITIONS†		MAX	UNIT
$t_{on}$	Turn-On Time	$V_{CC} = -30$ V,	$I_C = -500$ mA,	100	ns
$t_s$	Storage Time	$I_B(1) = -50$ mA,	$I_B(2) = 50$ mA,	350	ns
$t_f$	Fall Time	$V_{BE(off)} = 3.8$ V,	See Figure 1	50	ns

† Voltage and current values shown are nominal, exact values vary slightly with transistor parameters.

\* JEDEC registered data

## PARAMETER MEASUREMENT INFORMATION



NOTES: a. The input waveform is supplied by a generator with the following characteristics:  $Z_{out} = 50 \Omega$ ,  $t_r \leq 20$  ns,  $t_f \leq 20$  ns,  $t_w \approx 10 \mu s$ , duty cycle  $\leq 2\%$ .

b. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r \approx 10$  ns,  $R_{in} \geq 100$  k $\Omega$ .

**FIGURE 1—500-mA SWITCHING TIMES**

## THERMAL INFORMATION

